

**In the Claims:**

This listing of claims will replace all prior versions, and listing, of claims in the application:

5 1. (canceled)

2. (canceled)

3. (canceled)

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4. (canceled)

5. (currently amended) A method of constructing an electronic system from a set of components comprising:

15 selecting one or more key system parameters,  
creating a model of the system based on component performance,  
performing a sensitivity analysis on the model to identify critical components  
and parameters of those components required to meet the key system parameters,  
associating an identifier with each of the critical components,  
20 performing tests on the identified critical components to measure the identified  
parameters producing a set of measurements for each critical component,  
associating the set of measurements with the critical component,  
storing the set of measurements as an entry in a database,  
associating the database entry with an identifier for the critical components,  
25 selecting individual critical components for assembly into a system based on  
the associated measurements such that the resulting system meets the key system  
parameters, and  
assembling the system using the measurements associated with the  
components.

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6. (Previously presented) The method of Claim 5 where the identifier for the critical component is a serial number.

7. (Previously presented) The method of Claim 5 where the identifier for the critical component is a sequence number.

8. (Previously presented) The method of Claim 5 where the identifier for the critical component is a location in a component carrier.

9. (canceled)

10. (Previously presented) The method of Claim ~~5~~ 2 where assembling the system using the measurements associated with the critical components further comprises:  
assembling the system from a set of components,  
retrieving the measurements associated with each of the set of identified critical components, and  
calculating system calibration coefficients using the retrieved measurements.

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11. (Previously presented) The method of Claim 10 where associating the set of measurements further comprises storing the set of measurements in a memory which is part of the critical component.

12. (Previously presented) The method of Claim 10 where associating the set of measurements further comprises storing the set of measurements in a memory which is attached to the critical component.

13. (Previously presented) The method of Claim 10 where associating the set of measurements further comprises storing the set of measurements as an entry in a database, and  
associating the database entry with an identifier for the critical component.

14. (Previously presented) The method of Claim 13 where the identifier for the critical component is a serial number.

15. (Previously presented) The method of Claim 13 where the identifier for the critical component is a sequence number.

16. (Previously presented) The method of Claim 13 where the identifier for the critical component is a location in a component carrier.

17. (original) The method of Claim 10 where associating the set of measurements  
5 further comprises grouping components according to measurements.